

Notice of References CitedApplication/Control No.
09/934,625Applicant(s)/Patent Under
Reexamination
SAKO ET ALExaminer
TAN X. DINHArt Unit
2653

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,038,208 A	03-2000	Shikunami et al.	369/275.3
	B	US-5,684,785	11-1997	Itami et al.	369/275.2
	C	US-5,241,531 A	08-1993	Ohno et al.	369/275.2
	D	US-6,707,784 B2	03-2004	Sako et al.	369/275.3
	E	US-6,580,684	06-2003	Miyake et al.	369/275.3
	F	US-6,549,489 B1	04-2003	Van Der Enden et al.	369/30.11
	G	US-6,424,615 B1	07-2002	Ishimura et al.	369/275.3
	H	US-6,310,854 B1	10-2001	Sato et al.	369/275.3
	I	US-6,151,281 A	11-2000	Van Der Enden et al.	369/30.11
	J	US-6,078,559 A	06-2000	Takemura et al.	369/275.3
	K	US-6,031,808 A	02-2000	Ueno, Ichiro	369/111
	L	US-5,812,519 A	09-1998	Kawamura et al.	369/275.1
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.